

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application.

Listing of Claims:

Claims 1-2 (Canceled)

Claim 3 (Currently amended): The method of ~~claim 1~~ claim 56, wherein said step of testing further comprises testing a plurality of electronic devices at said test station using said transmitted test data.

Claim 4 (Currently amended): The method of ~~claim 1~~ claim 56, wherein said test data comprises commands and said step of testing an electronic device comprises said test station executing said commands and thereby running said plurality of tests on said electronic device.

Claim 5 (Previously presented): The method of claim 4, wherein said electronic device comprises self-test circuitry and said step of executing commands comprises said test station initiating operation of said self-test circuitry.

Claim 6 (Currently amended): The method of ~~claim 1~~ claim 56, wherein said ~~[[test]]~~ system further comprises a plurality of test stations, and said step of transmitting test data comprises transmitting test data to at least two of said test stations.

Claim 7 (Previously presented): The method of claim 6, wherein test data transmitted to each of said at least two test stations is the same.

Claim 8 (Original): The method of claim 6, wherein test data transmitted to at least one of said test stations is different than test data transmitted to another of said test stations.

Claim 9 (Previously presented): The method of claim 6, wherein said step of testing comprises testing at each of said at least two test stations an electronics device at said test station using test data transmitted to said test station.

Claim 10 (Previously presented): The method of claim 9 further comprising transmitting from each of said at least two test stations results of testing said electronic device at said test station.

Claim 11-12 (Canceled)

Claim 13 (Currently amended): A method of testing in a system comprising a tester and a test station, said method comprising:

- transmitting a test directive wirelessly from said tester to said test station; and
- running at said test station a test on an electronic device in accordance with said test directive, wherein:

- said [[test]] system comprises a plurality of testers,
- said step of transmitting [[test data]] comprises a first tester of said plurality of testers transmitting first test data to said test station;

- said step of [[testing]] running a test on an electronic device comprises performing a first test on said electronic device in accordance with said first test data;

- said method further comprising
 - transmitting second test data wirelessly from a second tester of said plurality of testers to said test station; and
 - performing a second test on said electronic device at said test station in accordance with said second test data.

Claim 14 (Original): The method of claim 13, wherein said first test and said second test are different tests.

Claim 15 (Previously presented): The method of claim 13, wherein a plurality of said electronic devices are disposed at said test station, and said first test is performed on a first subset of said plurality of electronic devices, and said second test is performed on a second subset of said plurality of electronic devices.

Claim 16 (Currently amended): The method of claim 1 claim 56, wherein said test station comprises a probe and said electronic device comprises a semiconductor wafer.

Claim 17 (Currently amended): The method of ~~claim 1~~ claim 56, wherein said electronic device comprises a packaged semiconductor die.

Claim 18 (Currently amended): The method of ~~claim 1~~ claim 56, wherein said electronic device comprises a singulated, unpackaged semiconductor die.

Claim 19 (Currently amended): The method of ~~claim 1~~ claim 56, wherein said electronic device comprises a multi-chip module.

Claims 20-55 (Canceled)

Claim 56 (Currently amended): A method of testing in a system comprising a tester and a test station, said method comprising:

transmitting a test directive wirelessly from said tester to said test station;
running at said test station a test on an electronic device in accordance with said test directive; [[and]]
transmitting results of said test wirelessly from said test station to said tester; and
adding another test station to said test system

wherein:

the transmitting step comprises transmitting test data wirelessly from said tester to said test station, said test data representing a plurality of tests for testing an electronic device;

the running step comprises testing said electronic device by running said plurality of tests on said electronic device at said test station; and

said step of adding another test station comprises said other test station transmitting wirelessly to said tester a request to be added to said test system.

Claim 57 (Previously presented): The method of claim 56, wherein said test directive comprises a command, and said running step comprises said test station decoding said command.

Claim 58 (Previously presented): The method of claim 56, wherein said test directive comprises a command, and said running step comprises said test station executing said command and thereby running said test on said electronic device.

Claim 59 (Previously presented): The method of claim 56, wherein said test directive comprises a test vector comprising data and locations to which said data is to be written.

Claim 60 (Previously presented): The method of claim 59, wherein said locations comprise identifications of probes through which said test data is to be written to said electronic device.

Claim 61 (Previously presented): The method of claim 56, wherein:

said transmitting step comprises transmitting a plurality of test directives wirelessly from said tester to said test station; and

said running step comprises running at said test station a plurality of tests on said electric electronic device in accordance with said test directives.

Claim 62 (Previously presented): The method of claim 13, wherein:

the transmitting step comprises transmitting test data wirelessly from said tester to said test station, said test data representing a plurality of tests for testing an electronic device; and

the running step comprises testing said electronic device by running said plurality of tests on said electronic device at said test station.